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☐	L12	l8 and fork$3 with walk$3 with (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or semi conduct$7 or memor$7 or stor$4 or register$4 or array)and (test$3 or detect$3 or debug$4)	3
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☐	L10	l8 and fork$3 with walk$3 with (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or semi conduct$7 or memor$7 or stor$4 or register$4 or array) same (test$3 or detect$3 or debug$4)	0
☐	L9	l8 and fork$3 with walk$3 with (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or semi conduct$7 or memor$7 or stor$4 or register$4 or array) same (test$3 or detect$3 or debug$4)	0
☐	L8	fork$3 with walk$3	298
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